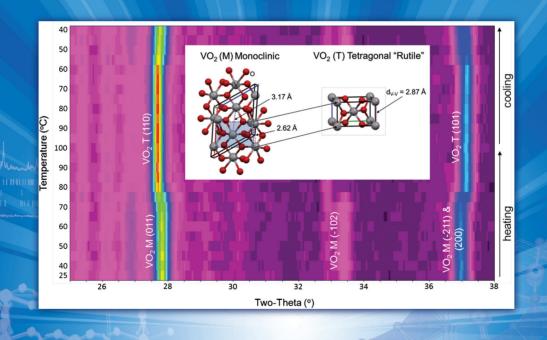
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On the Cover: From Figures 6 and 1. Monoclinic-Tetragonal phase transformation of VO₂ between room temperature and 100°C (air atmosphere). Monoclinic VO₂ (left) showing two distinct V-V bond distances, and tetragonal VO₂ (right) displaying the Rutile-like structure and single V-V distance. (Courtesy Mark A. Rodriguez, Nelson S. Bell, James J. M. Griego, Cynthia V. Edney, and Paul G. Clem).

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Back-Number Prices. 2014 single copies: \$75.

Subscription, renewals, and address changes should be addressed to Subscription Fulfillment, *Powder Diffraction*, Cambridge University Press, 100 Brook Hill Drive, West Nyack, NY 10013-2113 (for U.S.A., Canada, and Mexico); or Cambridge University Press, The Edinburgh Building, Shaftsbury Road, Cambridge, CB2 8RU, Cambridge, England (for UK and elsewhere). Allow at least six weeks advance notice. For address changes please send both old and new addresses and, if possible, include a mailing label from the wrapper of a recent issue.

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Powder Diffraction (ISSN: 0885-7156) is published quarterly (4X annually) by the JCPDS-International Centre for Diffraction Data through Cambridge University Press, 32 Avenue of the Americas, New York, NY 10013-2473. POSTMASTER: Send address changes to Powder Diffraction, Cambridge University Press, 100 Brook Hill Drive West Nyack, NY 10994-2113, USA. Periodicals postage paid in New York, NY and additional mailing offices.

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